

Docket No.: MUH-11671

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E. Willis  
10-30-01

J1011 U.S. PRO  
09/931686  
08/16/01

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : STEPHAN APPEN ET AL.

Filed : Concurrently herewith

Title : APPARATUS FOR THE AUTOMATED TESTING, CALIBRATION  
AND CHARACTERIZATION OF TEST ADAPTERS

INFORMATION DISCLOSURE STATEMENT

Hon. Commissioner of Patents and Trademarks,  
Washington, D.C. 20231

Sir:

In accordance with 37 C.F.R. 1.98 copies of the following patents and/or publications  
are submitted herewith:

U. S. Patent 4,471,298 (Frohlich), dated September 11, 1984;

U. S. Patent 4,904,934 (Nishihashi et al.), dated February 27, 1990;

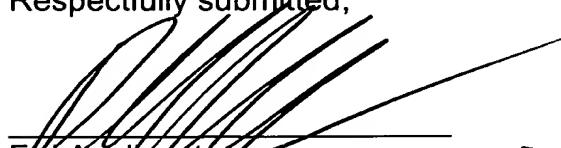
International Patent Application PCT/GB98/03262 (Vinson et al.), dated May 14,  
1999;

U. K. Patent Application GB 2 240 435 (Barker), dated July 31, 1991;

German Published, Non-Prosecuted Patent Application DE 44 41 347 A1 (Fritzsche),  
dated May 30, 1996, pertains to an adapting device for the testing of printed circuits.

If no translation of pertinent portions of any foreign language patents or publications mentioned above is included with the aforementioned copies of those applications, patents and/or publications, it is because no existing translation is readily available to the applicant.

Respectfully submitted,

  
For Applicants

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